•	Search Notes			

	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/516,947	FUJII ET AL.	
	Examiner	Art Unit	
_	Ching Chang	3748	

	SEAR	CHED	
Class	Subclass	Date	Examiner
123	90.16	07/15/07	U
13	90.2		
13	90.39		
13	90.44		
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INT	ERFERENC	FERENCE SEARCHED	
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMF	
Inventors Search	07/25/07	U	
Assigner Search			
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